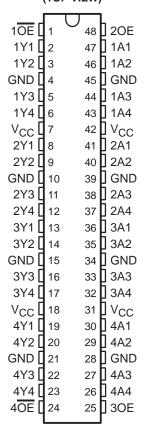
- Members of the Texas Instruments
 Widebus™ Family
- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power Dissipation
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- I_{off} and Power-Up 3-State Support Hot Insertion
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54LVTH16241 . . . WD PACKAGE SN74LVTH16241 . . . DGG OR DL PACKAGE (TOP VIEW)



description

These 16-bit buffers/drivers are designed specifically for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

The devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. The devices provide noninverting outputs and complementary output-enable (OE and \overline{OE}) inputs.

When V_{CC} is between 0 and 1.5 V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, \overline{OE} should be tied to V_{CC} through a pullup resistor and OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking/current-sourcing capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.



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SN54LVTH16241, SN74LVTH16241 3.3-V ABT 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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description (continued)

These devices are fully specified for hot-insertion applications using I_{off} and power-up 3-state. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.

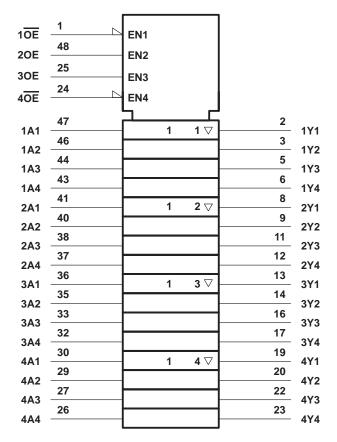
The SN54LVTH16241 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVTH16241 is characterized for operation from –40°C to 85°C.

FUNCTION TABLES

INPU [*]	OUTPUTS					
10E, 40E	1A, 4A	1Y, 4Y				
L	Н	Н				
L	L	L				
Н	Χ	Z				

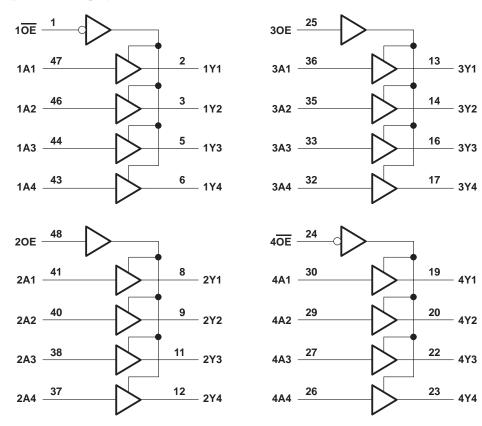
INPU'	OUTPUTS				
20E, 30E	2Y, 3Y				
Н	Н	Н			
Н	L	L			
L	X	Z			

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} –	0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance	
or power-off state, V _O (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state, V _O (see Note 1)0.5 V to	
Current into any output in the low state, IO: SN54LVTH16241	96 mA
SN74LVTH16241	
Current into any output in the high state, IO (see Note 2): SN54LVTH16241	48 mA
SN74LVTH16241	64 mA
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	
Package thermal impedance, θ _{JA} (see Note 3): DGG package	
DL package	94°C/W
Storage temperature range, T _{stg} 6	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

		SN54LVTI	H16241	SN74LVTI	UNIT		
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	2.7	3.6	2.7	3.6	V	
VIH	High-level input voltage	2	, A	2		V	
V _{IL}	Low-level input voltage		0.8		0.8	V	
VI	Input voltage	6	5.5		5.5	V	
IOH	High-level output current	6	-24		-32	mA	
loL	Low-level output current	25	48		64	mA	
Δt/Δν	Input transition rise or fall rate	Outputs enabled	00	10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate	200		200		μs/V	
T _A	Operating free-air temperature	-55	125	-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

SN54LVTH16241, SN74LVTH16241 3.3-V ABT 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN5	4LVTH16	6241	SN7	UNIT				
				MIN	TYP†	MAX	MIN	TYP†	MAX	UNII		
VIK		$V_{CC} = 2.7 \text{ V},$	I _I = -18 mA			-1.2			-1.2	V		
VOH		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V},$	I _{OH} = -100 μA	V _{CC} -0	.2		V _{CC} -0	.2				
		$V_{CC} = 2.7 \text{ V},$	I _{OH} = -8 mA	2.4			2.4			٧		
		V _{CC} = 3 V	I _{OH} = -24 mA	2								
		VCC = 3 V	$I_{OH} = -32 \text{ mA}$		2							
		V _{CC} = 2.7 V	I _{OL} = 100 μA			0.2			0.2			
		VCC = 2.7 V	$I_{OL} = 24 \text{ mA}$			0.5			0.5			
VOL			I _{OL} = 16 mA			0.4			0.4	V		
VOL		V _{CC} = 3 V	$I_{OL} = 32 \text{ mA}$			0.5			0.5	·		
		VCC = 3 V	$I_{OL} = 48 \text{ mA}$			0.55						
	_		$I_{OL} = 64 \text{ mA}$					0.55				
		$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V			10			10			
۱.	Control inputs	$V_{CC} = 3.6 \text{ V},$	$V_I = V_{CC}$ or GND			<u> ±</u> 1			±1	μΑ		
11	Data in auto	V _{CC} = 3.6 V	AI = ACC		d	1			1			
	Data inputs	VCC = 3.0 V	V _I = 0		PE	– 5			– 5			
l _{off}	$V_{CC} = 0$,		V_I or $V_O = 0$ to 4.5 V		2	±100			±100	μΑ		
	Data inputs	VCC = 3 V	V _I = 0.8 V	75	5		75					
l(hold)			ACC = 2 A	V _I = 2 V	-75	9		-75			μΑ	
i(noid)		$V_{CC} = 3.6 V^{\ddagger}$,	V _I = 0 to 3.6 V	A A					500 -750	μιτ		
lozh		V _{CC} = 3.6 V,	VO = 3 V			5			5	μΑ		
lozL		V _{CC} = 3.6 V,	V _O = 0.5 V			-5			- 5	μΑ		
I _{OZPU}		$V_{CC} = 0$ to 1.5 V, $V_{O} = 0$ OE/OE = don't care	0.5 V to 3 V,			±100*			±100	μА		
l _{OZPD}	$V_{CC} = 1.5 \text{ V to } 0, V_{O} = 0$ $OE/OE = don't care$		0.5 V to 3 V,			±100*			±100	μА		
Icc		V _{CC} = 3.6 V, I _O = 0,	Outputs high			0.19			0.19			
			Outputs low			5			5	mA		
		$V_I = V_{CC}$ or GND	Outputs disabled			0.19			0.19			
ΔI_{CC}		V _{CC} = 3 V to 3.6 V, One Other inputs at V _{CC} or 0	One input at V _{CC} – 0.6 V, c or GND			0.2			0.2	mA		
Ci		V _I = 3 V or 0	V _I = 3 V or 0		4		4			pF		
Co		V _O = 3 V or 0			9			9		pF		

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

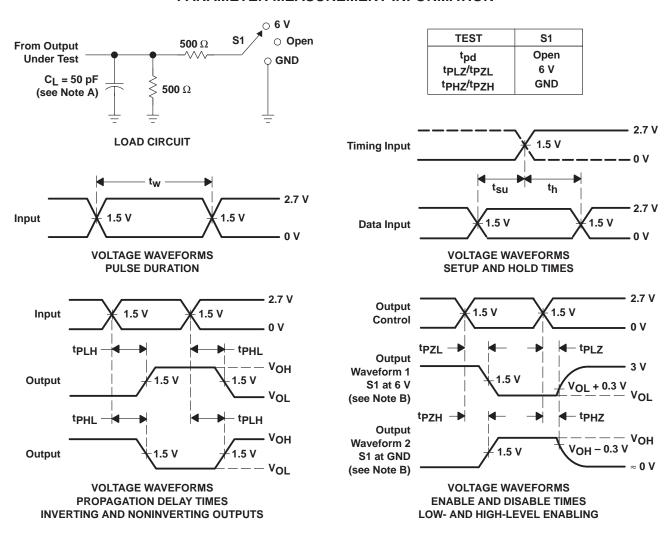
[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

			SN54LVTH16241			SN74LVTH16241									
PARAMETER	FROM (INPUT)	-	-	_	_	TO (OUTPUT)		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} $ $V_{CC} = 2.7 \text{ V}$		V _{CC} = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	MIN	TYP [†]	MAX	MIN	MAX				
t _{PLH}	А	Y	1.1	3.7	2	4	1.2	2.6	3.5		3.8	ns			
t _{PHL}		•	1.1	3.7	4	4	1.2	2.2	3.5		3.8	115			
^t PZH	OE or OE	Y	1.1	4.7	46	5.3	1.2	3.2	4.5		5.1	ns			
t _{PZL}		•	1.1	4.7	٧,	5.2	1.2	3.2	4.5		4.9	115			
^t PHZ	OE or OE	>	1.9	5.5		6.1	2	3.7	5.3		5.9	ns			
tPLZ		ſ	1.9	5.2		5.7	2	3.4	4.9		5.4	115			
tsk(o)				0					0.5		0.5	ns			

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2.5 ns. $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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